N-Channel Power MOSFET 500 V, 0.52 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	NDF	Unit
Drain-to-Source Voltage	V_{DSS}	500	V
Continuous Drain Current, R ₀ JC (Note 1)	I _D	12	Α
Continuous Drain Current $T_A = 100$ °C, $R_{\theta JC}$ (Note 1)	I _D	7.4	А
Pulsed Drain Current, t _P = 10 μs	I _{DM}	44	А
Power Dissipation, $R_{\theta JC}$	P _D	39	W
Gate-to-Source Voltage	V_{GS}	±30	V
Single Pulse Avalanche Energy, I _D = 10 A	E _{AS}	420	mJ
ESD (HBM) (JESD22-A114)	V _{esd}	4000	V
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 14)	V _{ISO}	4500	V
Peak Diode Recovery (Note 2)	dv/dt	4.5	V/ns
MOSFET dV/dt	dV/dt	60	V/ns
Continuous Source Current (Body Diode)	I _S	12	А
Maximum Temperature for Soldering Leads	T _L	260	°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

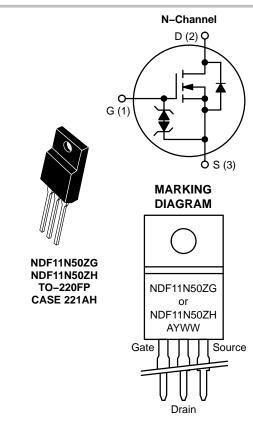
- 1. Limited by maximum junction temperature 2. $I_d \le 10.5 \text{ A}$, $di/dt \le 200 \text{ A/µs}$, $V_{DD} \le BV_{DSS}$, $T_J \le 150^{\circ}\text{C}$.



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V _{DSS}	R _{DS(ON)} (MAX) @ 4.5 A	
500 V	0.52 Ω	



= Location Code

= Year

WW = Work Week

G, H = Pb-Free, Halogen-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

THERMAL RESISTANCE

Parameter	Symbol	NDF11N50Z	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	3.2	°C/W
Junction-to-Ambient Steady State (Note 3)	$R_{\theta JA}$	50	

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$		BV _{DSS}	500			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C, $I_D = 1 \text{ mA}$		$\Delta BV_{DSS}/\Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	V 500 V V 0 V	25°C	I _{DSS}			1 μΑ	
	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$	125°C				50	1
Gate-to-Source Forward Leakage	V _{GS} = ±20 V		I _{GSS}			±10	μΑ
ON CHARACTERISTICS (Note 4)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$	٨	R _{DS(on)}		0.48	0.52	Ω
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 100 \mu A$		V _{GS(th)}	3.0	3.9	4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 4.5 A		9FS		7.7		S
OYNAMIC CHARACTERISTICS					•		•
Input Capacitance (Note 5)	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		C _{iss}	1097	1375	1645	pF
Output Capacitance (Note 5)			C _{oss}	132	166	199	
Reverse Transfer Capacitance (Note 5)			C _{rss}	30	40	50	
Total Gate Charge (Note 5)	V _{DD} = 250 V, I _D = 10.5 A, V _{GS} = 10 V		Qg	23	46	69	nC
Gate-to-Source Charge (Note 5)			Q _{gs}	4.5	8.7	13	
Gate-to-Drain ("Miller") Charge (Note 5)			Q _{gd}	12.5	25	37.5	
Plateau Voltage			V _{GP}		6.2		V
Gate Resistance			R_{g}		1.4		Ω
RESISTIVE SWITCHING CHARACTER	STICS				•		
Turn-On Delay Time			t _{d(on)}		15		ns
Rise Time	$V_{DD} = 250 \text{ V}, I_D = 10.5$	Α,	t _r		32		1
Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 5 \Omega$		t _{d(off)}		40		1
Fall Time			t _f		23		
OURCE-DRAIN DIODE CHARACTER	ISTICS (T _C = 25°C unless other	erwise not	ed)				
Diode Forward Voltage	$I_S = 10.5 \text{ A}, V_{GS} = 0 \text{ V}$		V _{SD}			1.6	V
Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 30 \	/	t _{rr}		310		ns
Reverse Recovery Charge	$I_S = 10.5 \text{ A}, \text{ di/dt} = 100 \text{ A}$		Q _{rr}		2.5		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- Insertion mounted
 Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.
 Guaranteed by design.

TYPICAL CHARACTERISTICS

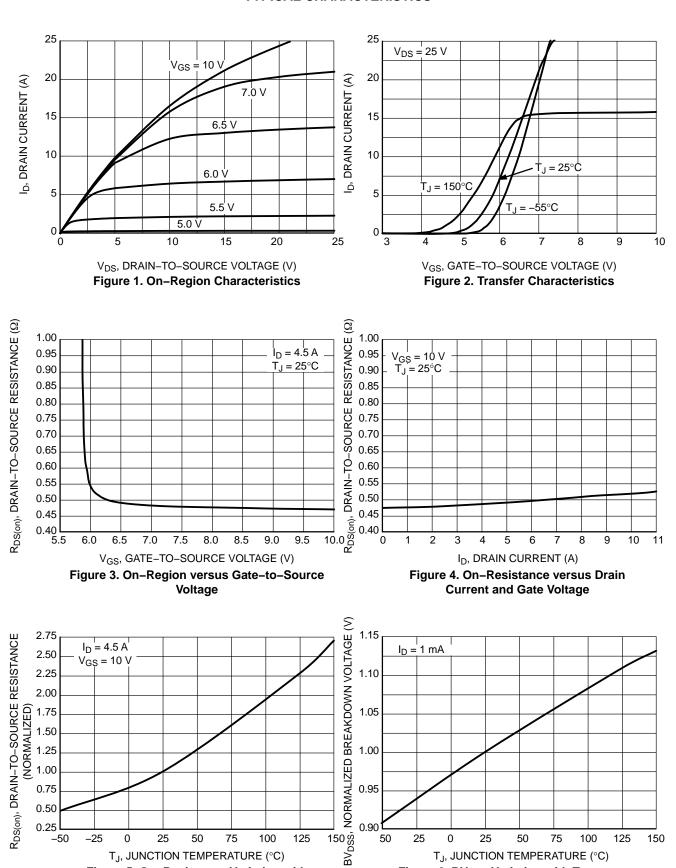


Figure 6. BV_{DSS} Variation with Temperature

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS

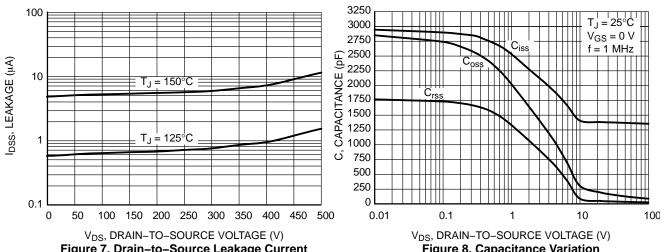
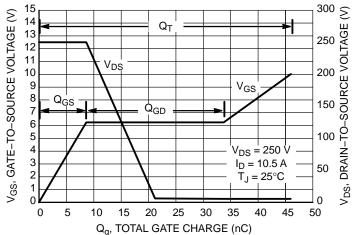


Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation



 ${\bf Q}_g,$ TOTAL GATE CHARGE (nC) Figure 9. Gate–to–Source Voltage and Drain-to-Source Voltage versus Total Charge

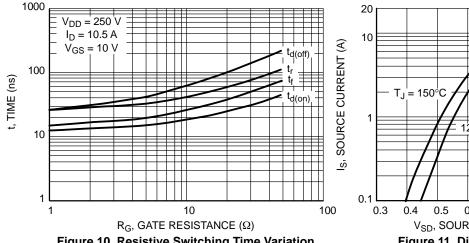


Figure 10. Resistive Switching Time Variation versus Gate Resistance

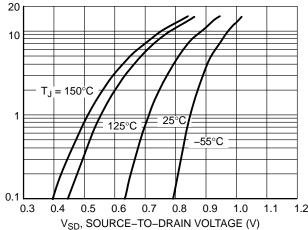


Figure 11. Diode Forward Voltage versus Current

TYPICAL CHARACTERISTICS

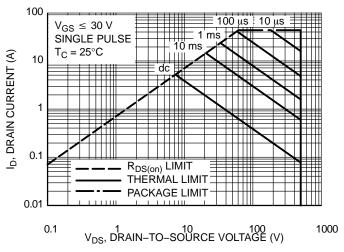


Figure 12. Maximum Rated Forward Biased Safe Operating Area NDF11N50Z

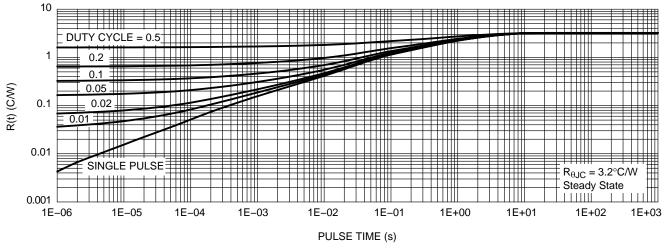


Figure 13. Thermal Impedance (Junction-to-Case) for NDF11N50Z

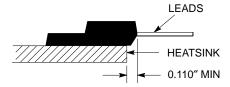


Figure 14. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

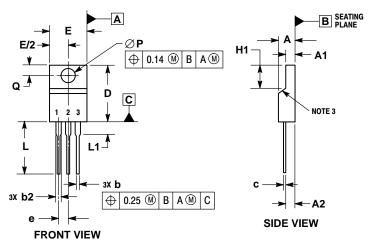
ORDERING INFORMATION

Order Number	Package	Shipping
NDF11N50ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF11N50ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail

PACKAGE DIMENSIONS

TO-220 FULLPACK, 3-LEAD

CASE 221AH ISSUE F

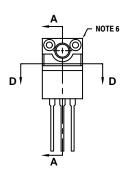


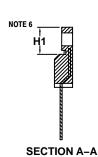
NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. CONTOUR UNCONTROLLED IN THIS AREA.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO PROTHOSIONS, MOLD PLASH AND GALE PROTHOSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY. DIMENSION b2 DOES NOT INCLUDE DAMBAR PROTRUSION. LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.
- CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY MAY VARY WITHIN THE ENVELOP DEFINED BY DIMENSIONS AT AND H1 FOR MANUFACTURING PURPOSES.

	MILLIMETERS			
DIM	MIN	MAX		
Α	4.30	4.70		
A1	2.50	2.90		
A2	2.50	2.90		
b	0.54	0.84		
b2	1.10	1.40		
C	0.49	0.79		
D	14.70	15.30		
Е	9.70	10.30		
е	2.54	BSC		
H1	6.60	7.10		
L	12.50	14.73		
L1		2.80		
Р	3.00	3.40		
Q	2.80	3.20		







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